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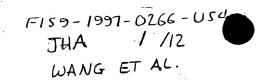
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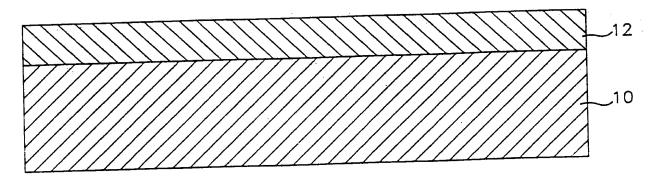


FIG. 1

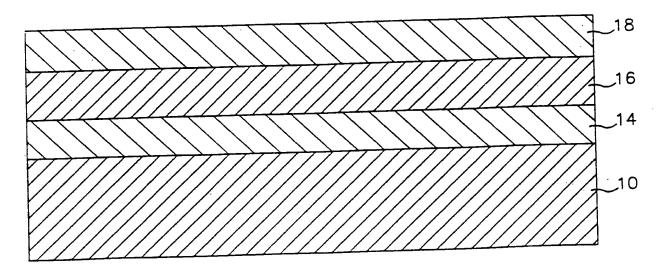


FIG. 2a

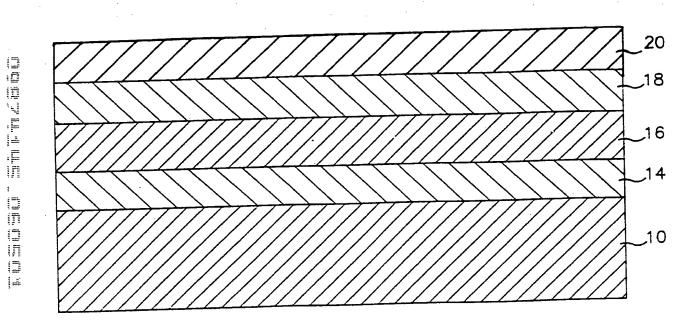
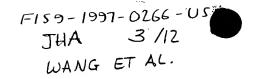


FIG. 2b



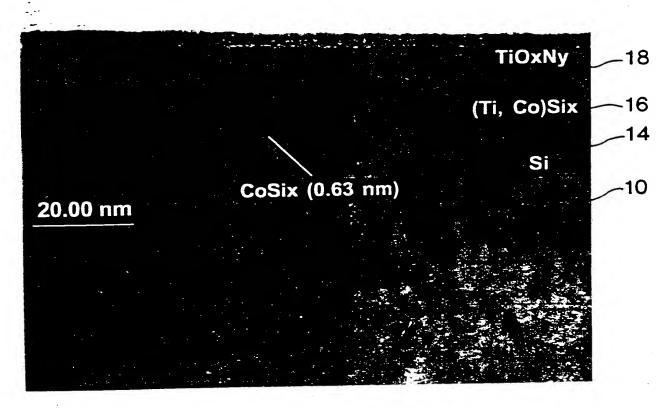


FIG. 3

JHA 4/12
WANG ET AL.

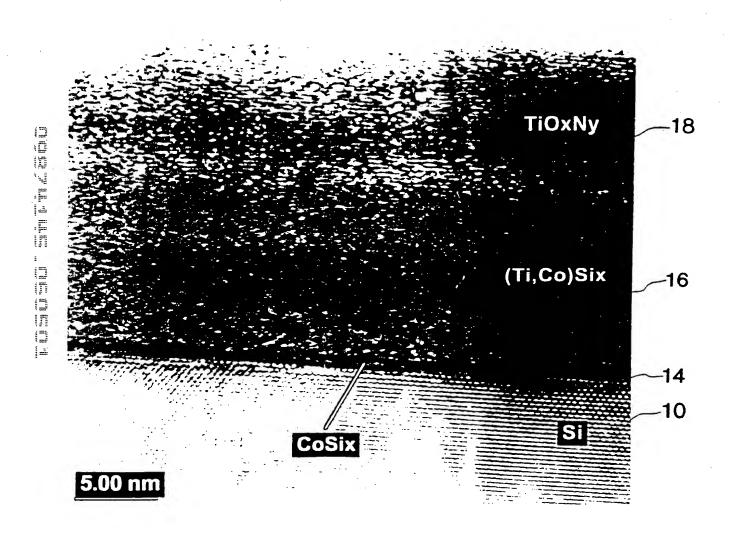


FIG. 4

JHA 5/12 WANG ET AL.

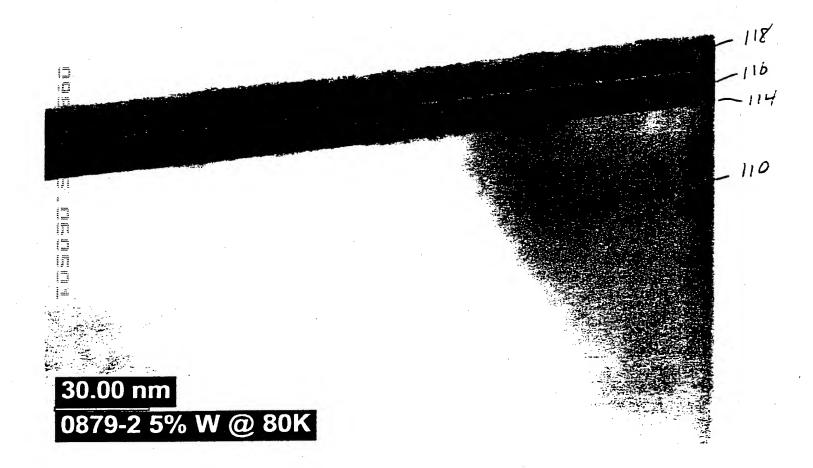


FIGURE 5

JHA 6/12

WANG ET AL.

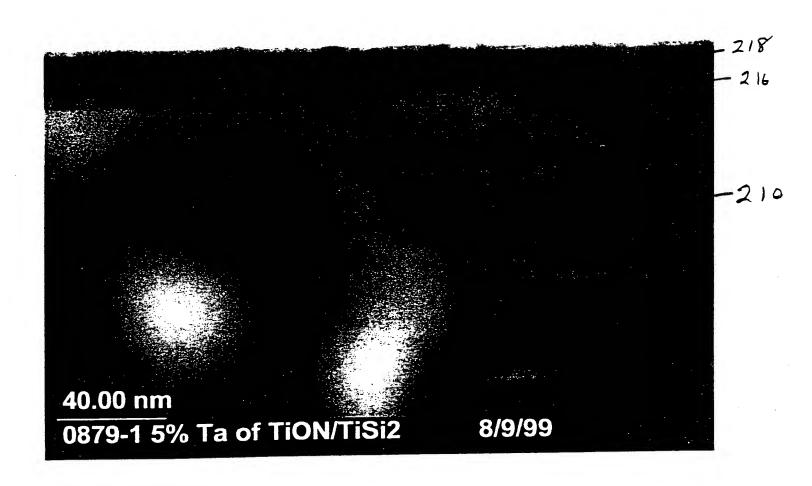


FIGURE 6

JHA 7/12 WANG ET AL.

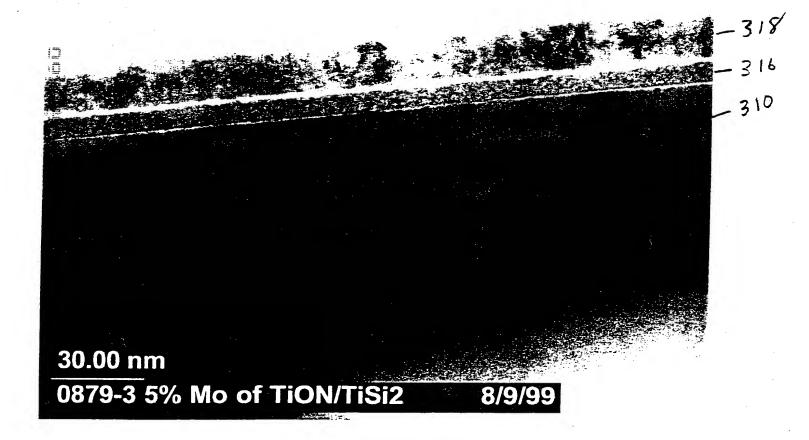


FIGURE 7

THA 8/12 WANG ETAL.

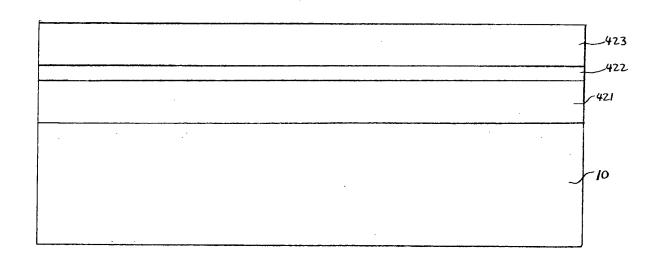


FIG. 8

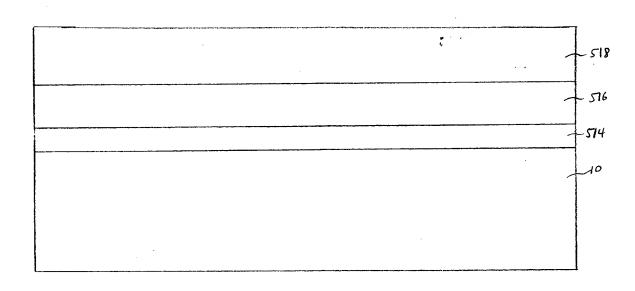


FIG.9



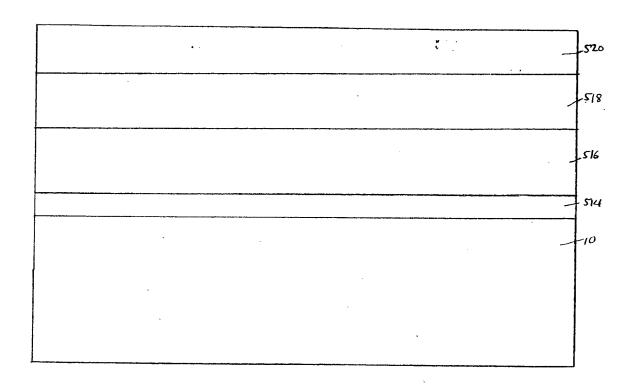


FIG. 10

FIS9-1997-0266-US4 JHA 11/12 WANG ET AL.

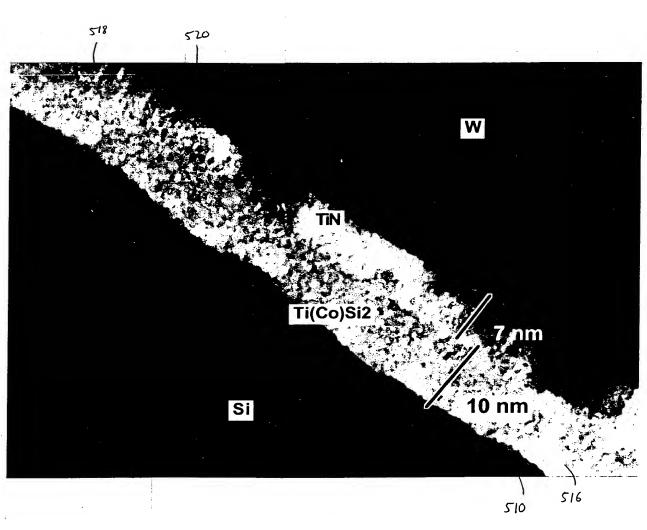
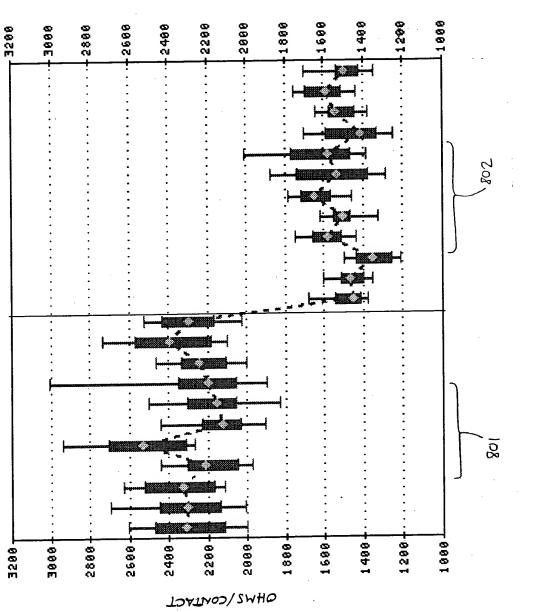


FIG. 11

F159-1997-0266-US4 12/12 JAA WANG ET AL.



Contact resistance

F1G. 12